Features

- No External Components Except PIN Diode
- Supply-voltage Range: 2.7 V to 3.6 V
- Available for Carrier Frequencies in the Range of 30 kHz to 56 kHz; Adjusted by Zener-diode Fusing
- Enhanced Bandpass Filter Accuracy of ±1.25%
- ESD: 4 kV HBM, 400 V MM
- Automatic Sensitivity Adaptation (AGC)
- Automatic Strong Signal Adaptation (ATC)
- Enhanced Immunity against Ambient Light Disturbances
- TTL and CMOS Compatible
- Suitable Minimum Burst Length ≥ 6 or 10 pulses

Applications

- Audio/Video Applications
- Home Appliances
- Remote Control Equipment

Description

The fully integrated IR receiver IC T2527 is designed to be used in all kinds of unidirectional infrared data transmission systems. It is especially optimized for carrier-frequency modulated transmission applications. Several built-in features enable best transmission quality.

The input stage has two functions: first to provide the bias voltage for the PIN diode and secondly to transform the photo current signal into a voltage for further internal processing. This is carried out by a special circuit that is optimized for low-noise applications due to the fact that the incoming current signal is as small as 700 pA. This voltage signal is amplified by a so-called Controlled Gain Amplifier (CGA) followed by a bandpass filter. The filter frequency and therefore the operating carrier frequency are defined by a narrow-tuned bandpass filter. The enhanced bandpass filter tunes the input signal very accurately with a tolerance of ±1.25%.

The input burst signal is demodulated and converted into a digital envelope output pulse. An integrated dynamic feedback circuit block (which varies the gain as a function of the present environmental conditions such as ambient light, modulated lamps etc.) makes sure that the signal information is evaluated and that unwanted pulses are suppressed at the output pin.

The operating supply voltage range for the T2527 is 2.7 V to 3.6 V.
**Figure 1.** Block Diagram

**Pad Layout**

**Figure 2.** Pad Layout 1 (DDW Only)

**Figure 3.** Pad Layout 2 (DDW, SO8 or TSSOP8)
**Pin Configuration**

*Figure 4.* Pinning SO8 and TSSOP8

<table>
<thead>
<tr>
<th>Pin</th>
<th>Symbol</th>
<th>Function</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>VS</td>
<td>Supply voltage</td>
</tr>
<tr>
<td>2</td>
<td>n.c.</td>
<td>Not connected</td>
</tr>
<tr>
<td>3</td>
<td>OUT</td>
<td>Data output</td>
</tr>
<tr>
<td>4</td>
<td>n.c.</td>
<td>Not connected</td>
</tr>
<tr>
<td>5</td>
<td>IN</td>
<td>Input PIN diode</td>
</tr>
<tr>
<td>6</td>
<td>GND</td>
<td>Ground</td>
</tr>
<tr>
<td>7</td>
<td>n.c.</td>
<td>Not connected</td>
</tr>
<tr>
<td>8</td>
<td>n.c.</td>
<td>Not connected</td>
</tr>
</tbody>
</table>

**Absolute Maximum Ratings**

<table>
<thead>
<tr>
<th>Parameters</th>
<th>Symbol</th>
<th>Value</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Supply voltage</td>
<td>$V_S$</td>
<td>-0.3 to +4.0 V</td>
<td>V</td>
</tr>
<tr>
<td>Supply current</td>
<td>$I_S$</td>
<td>2.0 mA</td>
<td>mA</td>
</tr>
<tr>
<td>Input voltage</td>
<td>$V_{IN}$</td>
<td>-0.3 to $V_S$</td>
<td>V</td>
</tr>
<tr>
<td>Input DC current at $V_S = 3$ V</td>
<td>$I_{IN}$</td>
<td>0.4 mA</td>
<td>mA</td>
</tr>
<tr>
<td>Output voltage</td>
<td>$V_O$</td>
<td>-0.3 to $V_S$</td>
<td>V</td>
</tr>
<tr>
<td>Output current</td>
<td>$I_O$</td>
<td>10 mA</td>
<td>mA</td>
</tr>
<tr>
<td>Operating temperature</td>
<td>$T_{amb}$</td>
<td>-25 to +85°C</td>
<td>°C</td>
</tr>
<tr>
<td>Storage temperature</td>
<td>$T_{str}$</td>
<td>-40 to +125°C</td>
<td>°C</td>
</tr>
<tr>
<td>Power dissipation at $T_{amb} = 25°C</td>
<td>$P_{tot}$</td>
<td>20 mW</td>
<td>mW</td>
</tr>
</tbody>
</table>

**Thermal Resistance**

<table>
<thead>
<tr>
<th>Parameters</th>
<th>Symbol</th>
<th>Value</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Junction ambient SO8</td>
<td>$R_{thJA}$</td>
<td>130</td>
<td>K/W</td>
</tr>
<tr>
<td>Junction ambient TSSOP8</td>
<td>$R_{thJA}$</td>
<td>TBD</td>
<td>K/W</td>
</tr>
</tbody>
</table>
### Electrical Characteristics

\( T_{\text{amb}} = -20^\circ\text{C} \) to \( +70^\circ\text{C} \), \( V_S = 2.7 \) V to 3.6 V unless otherwise specified.

<table>
<thead>
<tr>
<th>No.</th>
<th>Parameters</th>
<th>Test Conditions</th>
<th>Pin</th>
<th>Symbol</th>
<th>Min.</th>
<th>Typ.</th>
<th>Max.</th>
<th>Unit</th>
<th>Type*</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>Supply</td>
<td></td>
<td>1</td>
<td>( V_S )</td>
<td>2.7</td>
<td>3.0</td>
<td>3.6</td>
<td>V</td>
<td>C</td>
</tr>
<tr>
<td>1.1</td>
<td>Supply-voltage range</td>
<td></td>
<td>1</td>
<td>( I_S )</td>
<td>0.7</td>
<td>0.9</td>
<td>1.2</td>
<td>mA</td>
<td>B</td>
</tr>
<tr>
<td>2</td>
<td>Output</td>
<td></td>
<td>1.3</td>
<td>( R_{PU} )</td>
<td>30/40</td>
<td>k( \Omega )</td>
<td>A</td>
<td></td>
<td></td>
</tr>
<tr>
<td>2.1</td>
<td>Internal pull-up resistor (^{(1)})</td>
<td>( T_{\text{amb}} = 25^\circ\text{C}; ) see Figure 12</td>
<td>3, 6</td>
<td>( V_{OL} )</td>
<td>250</td>
<td>mV</td>
<td>B</td>
<td></td>
<td></td>
</tr>
<tr>
<td>2.2</td>
<td>Output voltage low</td>
<td>( R_2 = 2.4 ) k( \Omega ); see Figure 12</td>
<td>3, 1</td>
<td>( V_{DH} )</td>
<td>( V_S - 0.25 )</td>
<td>Vs</td>
<td>V</td>
<td></td>
<td></td>
</tr>
<tr>
<td>2.3</td>
<td>Output voltage high</td>
<td></td>
<td>3, 6</td>
<td>( I_{OCL} )</td>
<td>8</td>
<td>mA</td>
<td>B</td>
<td></td>
<td></td>
</tr>
<tr>
<td>3</td>
<td>Input</td>
<td></td>
<td>5</td>
<td>( I_{\text{IN,Dcmax}} )</td>
<td>-150</td>
<td>( \mu\text{A} )</td>
<td>C</td>
<td></td>
<td></td>
</tr>
<tr>
<td>3.1</td>
<td>Input DC current ( V_{IN} = 0 ); see Figure 12</td>
<td>5</td>
<td>( I_{\text{IN,Dcmax}} )</td>
<td>-350</td>
<td>( \mu\text{A} )</td>
<td>B</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>3.2</td>
<td>Input DC current; see Figure 6</td>
<td>( V_{IN} = 0 ); ( V_S = 3 ) V, ( T_{\text{amb}} = 25^\circ\text{C} )</td>
<td>3</td>
<td>( I_{E\text{emin}} )</td>
<td>-700</td>
<td>( \text{pA} )</td>
<td>B</td>
<td></td>
<td></td>
</tr>
<tr>
<td>3.3</td>
<td>Min. detection threshold current; see Figure 5</td>
<td>Test signal: see Figure 11 ( V_S = 3 ) V, ( T_{\text{amb}} = 25^\circ\text{C} ), ( I_{\text{IN,DC}} = 1 ) ( \mu\text{A} ); square pp, burst ( N = 16 ); ( f = f_0 ); ( t_{\text{PER}} = 10 ) ms, Figure 10; BER = 50 (^{(2)})</td>
<td>3</td>
<td>( I_{E\text{emin}} )</td>
<td>-1500</td>
<td>( \text{pA} )</td>
<td>C</td>
<td></td>
<td></td>
</tr>
<tr>
<td>3.4</td>
<td>Min. detection threshold current with AC current disturbance ( I_{\text{IN,AC100}} = 3 ) ( \mu\text{A} ) at 100 Hz</td>
<td>( V_S = 3 ) V, ( T_{\text{amb}} = 25^\circ\text{C} ), ( I_{\text{IN,DC}} = 1 ) ( \mu\text{A} ); square pp, burst ( N = 16 ); ( f = f_0 ); ( t_{\text{PER}} = 10 ) ms, Figure 10; BER = 50 (^{(2)})</td>
<td>3</td>
<td>( I_{E\text{emin}} )</td>
<td>-200</td>
<td>( \mu\text{A} )</td>
<td>D</td>
<td></td>
<td></td>
</tr>
<tr>
<td>4</td>
<td>Controlled Amplifier and Filter</td>
<td></td>
<td></td>
<td>( G_{\text{VARMAX}} )</td>
<td>51</td>
<td>dB</td>
<td>D</td>
<td></td>
<td></td>
</tr>
<tr>
<td>4.1</td>
<td>Maximum value of variable gain (CGA)</td>
<td></td>
<td></td>
<td>( G_{\text{VARMIN}} )</td>
<td>-5</td>
<td>dB</td>
<td>D</td>
<td></td>
<td></td>
</tr>
<tr>
<td>4.2</td>
<td>Minimum value of variable gain (CGA)</td>
<td></td>
<td></td>
<td>( G_{\text{VARMAX}} )</td>
<td>51</td>
<td>dB</td>
<td>D</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

*) Type means: A = 100% tested, B = 100% correlation tested, C = Characterized on samples, D = Design parameter

Notes:
1. Depending on version, see “Ordering Information”.
2. BER = bit error rate; e.g., BER = 5% means that with \( P = 20 \) at the input Pin 19 to Pin 21 pulses can appear at the Pin OUT.
3. After transformation of input current into voltage.
### Electrical Characteristics (Continued)

$T_{\text{amb}} = -$20°C to +70°C, $V_S = 2.7$ V to 3.6 V unless otherwise specified.

<table>
<thead>
<tr>
<th>No.</th>
<th>Parameters</th>
<th>Test Conditions</th>
<th>Pin</th>
<th>Symbol</th>
<th>Min.</th>
<th>Typ.</th>
<th>Max.</th>
<th>Unit</th>
<th>Type*</th>
</tr>
</thead>
<tbody>
<tr>
<td>4.3</td>
<td>Total internal amplification $^{(3)}$</td>
<td></td>
<td></td>
<td>$G_{\text{MAX}}$</td>
<td>71</td>
<td></td>
<td></td>
<td>dB</td>
<td>D</td>
</tr>
<tr>
<td>4.4</td>
<td>Center frequency fusing accuracy of bandpass</td>
<td>$V_S = 3$ V, $T_{\text{amb}} = 25$°C</td>
<td></td>
<td>$f_{03V,\text{FUSE}}$</td>
<td>-1.25</td>
<td>$f_0$</td>
<td>+1.25</td>
<td>%</td>
<td>A</td>
</tr>
<tr>
<td>4.5</td>
<td>Overall accuracy center frequency of bandpass</td>
<td>See Figure 7</td>
<td></td>
<td>$f_{03V}$</td>
<td>-3.5</td>
<td>$f_0$</td>
<td>+2.0</td>
<td>%</td>
<td>C</td>
</tr>
<tr>
<td>4.6</td>
<td>BPF bandwidth</td>
<td>-3 dB; $f_0 = 38$ kHz; see Figure 9</td>
<td></td>
<td>B</td>
<td>3.8</td>
<td></td>
<td></td>
<td>kHz</td>
<td>C</td>
</tr>
</tbody>
</table>

*) Type means: A =100% tested, B = 100% correlation tested, C = Characterized on samples, D = Design parameter

Notes:  
1. Depending on version, see “Ordering Information”.  
2. BER = bit error rate; e.g., BER = 5% means that with $P = 20$ at the input Pin 19 to Pin 21 pulses can appear at the Pin OUT.  
3. After transformation of input current into voltage.

**ESD**


### Typical Electrical Curves at $T_{\text{amb}} = 25$°C

*Figure 5. $I_{\text{Eemin}}$ versus $I_{\text{IN,DC}}$, $V_S = 3$ V*
Figure 6. $V_{IN}$ versus $I_{IN,DC}$, $V_S = 3$ V

![Figure 6](image)

Figure 7. Overall Tolerance of Bandpass Inclusive Fusing

![Figure 7](image)

Figure 8. Data Transmission Rate, $V_S = 3$ V

![Figure 8](image)
**Figure 9.** Typical Bandpass Curve

![Bandpass Curve Diagram]

- $f_1 = 0.96$ (at -3 dB)
- $f_2 = f/f_0$
- $f_3 = 1.047$ (at -3 dB)
- $B = \text{bandwidth (-3 dB)}$
- $Q = f_2 / B$
- Example: $Q = 1 / (1.047 - 0.960) = 11.5$

**Figure 10.** Illustration of Used Terms

Example: $f = 30 \text{ kHz}$, burst with 16 pulses, 16 periods

- Period ($P = 16$)
- Burst ($N = 16$ pulses)
- Envelope
- Telegram pause
- Data word
- $T_{\text{REF}} = 62 \text{ ms}$
Figure 11. Test Circuit

![Test Circuit Diagram]

- $R_1 = 220 \, \Omega$
- $C_1 = 1 \, \text{nF}$
- $C_2 = 1 \, \text{nF}$
- $V_{DD} = 3 \, \text{V}$
- $I_{IN\_DC} = \frac{\Delta U_2}{40k}$
- $I_{Ee} = \frac{\Delta U_1}{400k}$
- $t_{PER} = 10\, \text{ms}$

Figure 12. Application Circuit

![Application Circuit Diagram]

- $R_1 = 220 \, \Omega$
- $R_2 > 2.4k \, \Omega$
- $C_1 = 470pF$
- $C_2 = 470pF$
- $V_{DD} = 3 \, \text{V}$
- $I_{IN\_DC}$
- $I_{Ee}$
- $I_{IN}$
- $T2527$
- $V_{O}$
- $\mu C$
- $I_{OCL}$
- $*)$ optional
**Chip Dimensions**

*Figure 13. Chip Size in µm (1)*

Note: 1. Pad coordinates are given for lower left corner of the pad in µm from the origin 0,0

<table>
<thead>
<tr>
<th>Parameters</th>
<th>Values</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Dimensions</strong></td>
<td></td>
</tr>
<tr>
<td>Length incl. scribe</td>
<td>1.16 mm</td>
</tr>
<tr>
<td>Width incl. scribe</td>
<td>1.37 mm</td>
</tr>
<tr>
<td>Thickness</td>
<td>290 µ ± 5%</td>
</tr>
<tr>
<td>Pads</td>
<td>90 µ x 90 µ</td>
</tr>
<tr>
<td>Fusing pads</td>
<td>70 µ x 70 µ</td>
</tr>
<tr>
<td><strong>Pad metallurgy</strong></td>
<td>AISiTi</td>
</tr>
<tr>
<td><strong>Finish</strong></td>
<td>Si₃N₄ thickness 1.05 µm</td>
</tr>
</tbody>
</table>
### Ordering Information

Delivery: unsawn wafers (DDW) in box, SO8 (150 mil) and TSSOP8 (3 mm body).

#### Extended Type Number

<table>
<thead>
<tr>
<th>Type</th>
<th>PL(2)</th>
<th>R_PU(3)</th>
<th>D(4)</th>
<th>Notes</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Standard type:</strong> ≥10 pulses, enhanced sensibility, high data rate</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>T2527N0xx(1)-yyy(5)</td>
<td>2</td>
<td>30</td>
<td>2000</td>
<td></td>
</tr>
<tr>
<td>T2527N1xx(1)-DDW</td>
<td>1</td>
<td>30</td>
<td>2000</td>
<td></td>
</tr>
<tr>
<td>T2527N2xx(1)-yyy(5)</td>
<td>2</td>
<td>40</td>
<td>1333</td>
<td></td>
</tr>
<tr>
<td>T2527N3xx(1)-DDW</td>
<td>1</td>
<td>40</td>
<td>1333</td>
<td></td>
</tr>
<tr>
<td><strong>Lamp type:</strong> ≥10 pulses, enhanced suppression of disturbances, secure data transmission</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>T2527N6xx(1)-yyy(5)</td>
<td>2</td>
<td>30</td>
<td>3060</td>
<td></td>
</tr>
<tr>
<td>T2527N7xx(1)-DDW</td>
<td>1</td>
<td>30</td>
<td>3060</td>
<td></td>
</tr>
<tr>
<td><strong>Short burst type:</strong> ≥6 pulses, enhanced data rate</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Notes:**
1. xx means the used carrier frequency value f₀ 30, 33, 36, 38, 40, 44 or 56 kHz (76 kHz type on request).
2. Two pad layout versions (see Figure 2 and Figure 3) available for different assembly demand.
3. Integrated pull-up resistor at PIN OUT (see electrical characteristics).
4. Typical data transmission rate up to bit/s with f₀ = 56 kHz, V_S = 3 V (see Figure 8).
5. yyy means kind of packaging: DDW -> unsawn wafers in box.
Package Information

Figure 14. SO8

Dimensions in mm

Figure 15. TSSO8

Dimensions in mm
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FAX (49) 71-31-67-2340

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